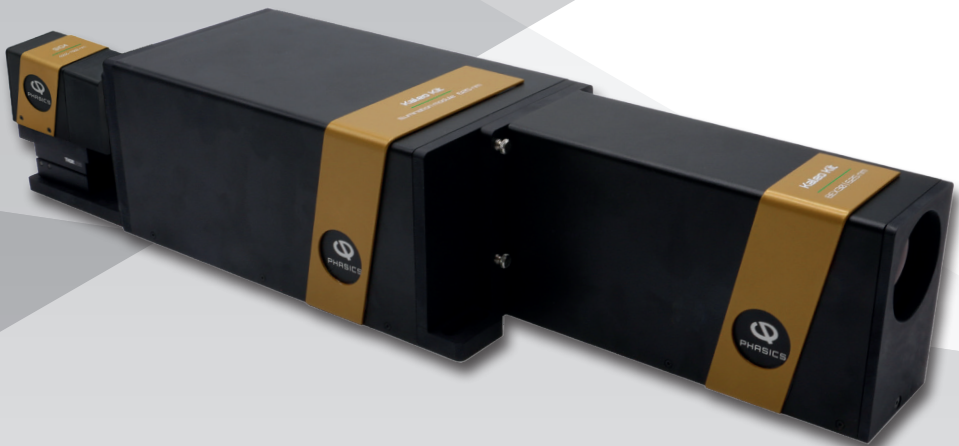
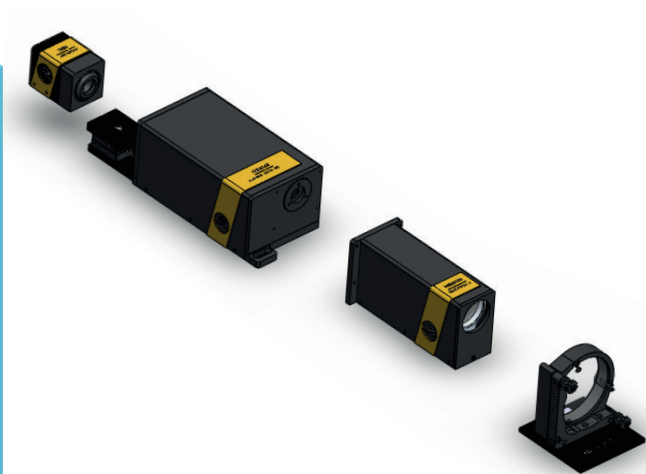


Kaleo Kit

Fully modular
metrology solution
from UV to IR

PHASICS
the phase control company



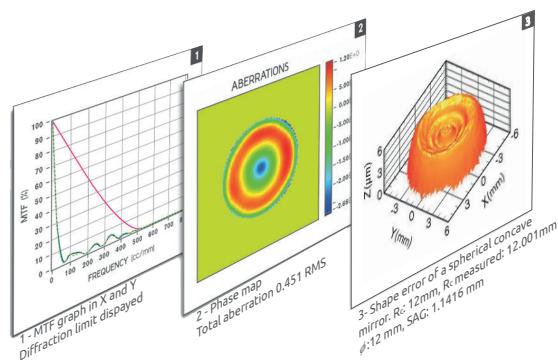


ASSEMBLE YOUR OWN MODULAR METROLOGY SYSTEM...

With the rise in complexity of optical systems, metrology teams often need **specific measurement parameters** (test wavelength, accuracy, resolution, relevant outcomes...). PHASICS answers this challenge with **Kaleo Kit**, its modular system for optics qualification.

Kaleo Kit is the combination of a broad range of compatible modules, that let you create a **cost-effective, compact, and easy-to-use system** that can adapt to a wide range of measurement configurations and ensure the quality of your sample at all development stages.

Access all the characteristics of your sample in a **single shot acquisition**: TWE, RWE, wavefront aberrations, MTF, PSF, and a lot more!



... IN JUST 3 EASY STEPS

1

Choose **YOUR**
Wavefront Sensor



SID4 Model	Spectral Range (nm)	Sampling (px)
SID4 UV	190-400	300x300
SID4	400-1100	182x136
SID4 HR	400-1100	416x360
SID4 UHR	400-1100	554x554
SID4 SWIR	900-1700	80x64
SID4 SWIR HR	900-1700	160x128
SID4 DWIR	3000-5000	160x120

2

Select **YOUR**
Illumination
module

Wavelength *
(nm)

365	810
405	850
530	940
625	1050
740	1550
780	3900

3

Shape **YOUR** beam

Beam Expander *
Exit pupil
diameter (mm)

15
30
60
100
130

OR

Focusing System *

VIS	F#	SWIR
0.4		
0.7		2.5
1.2		5
2.1		10
3.3		
5		
9		

+ Reference mirror (flat or sphere)

* more options upon request

ACCORDING TO YOUR SPECIFIC REQUIREMENTS

VERSATILE

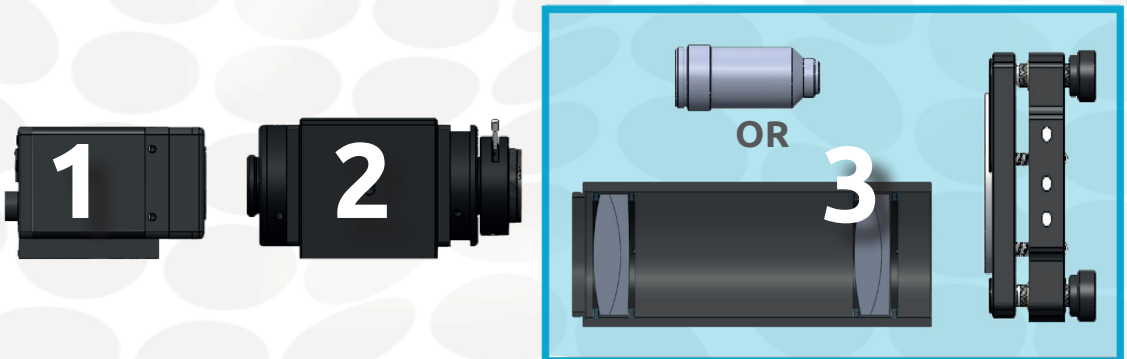
- Available from UV to IR
- Modules compatible with stand-alone use
- All measurement configurations: finite-finite, infinite-finite...
- Same modules fit for different setups

POWERFUL UNIQUE TECHNOLOGY

- High resolution
- Dedicated to large aberrations measurement
- Achromatic measurement: for any test wavelength
- Nanometric sensitivity

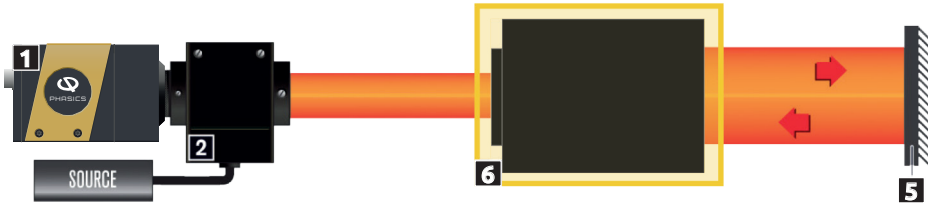
EASY-TO-USE

- Compact
- Designed for easy alignment
- Quick access to all results



ADAPTED TO ALL APPLICATIONS

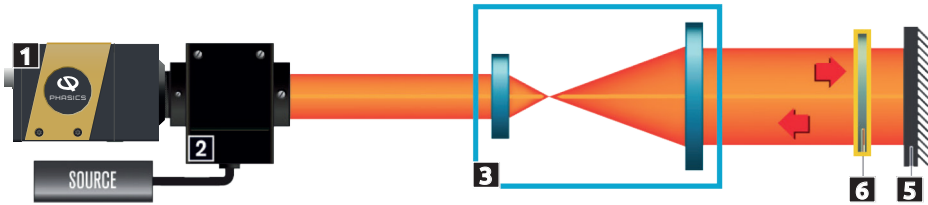
- Telescope alignment and characterization



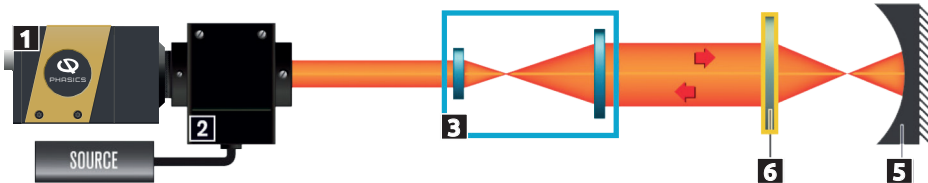
- Concave mirror measurement



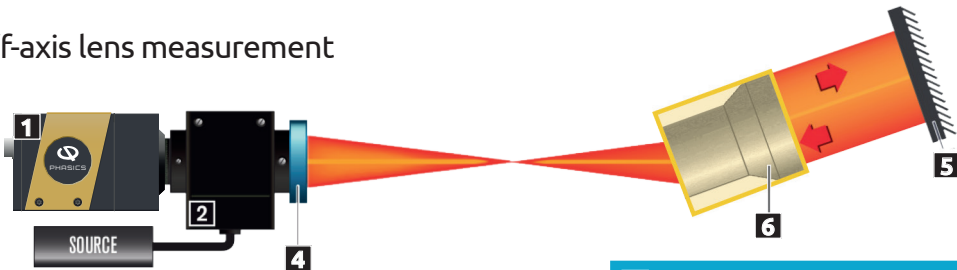
- Large diameter flat optics characterization: Filters, Windows, Polarizing optics



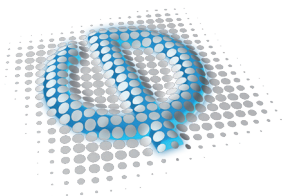
- Large diameter lens & objective measurement in any configuration



- Off-axis lens measurement



- 1 SID4 Wavefront sensor
 - 2 Illumination module
 - 3 Beam expander
 - 4 Focusing system
 - 5 Reference mirror
 - 6 System under test
- Kaleo Kit modules



PHASICS

the phase control company

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